

**Search Notes**

Application/Control No.

10/755,997

Examiner

Emmanuel S. Luk

Applicant(s)/Patent under  
Reexamination

BAILEY ET AL.

Art Unit

1722

**SEARCHED**

Class	Subclass	Date	Examiner
425	385	5/29/2006	EL
977	887	5/29/2006	EL

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
10/614,716	5/29/2006	EL
EAST text search	5/29/2006	EL